

<b>Notice of References Cited</b>	Application/Control No. <b>10/042,949</b>	Applicant(s)/Patent Under Reexam <b>Shibata et al</b>	
	Examiner <b>Edward Wojciechowicz</b>	Art Unit <b>2815</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	6,153,894	11/2000	Udagawa	257	96
B					
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**FOREIGN PATENT DOCUMENTS**

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